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Understanding Embedded - Microprocessors

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of Embedded - Microprocessors

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details	
Product Status	Obsolete
Core Processor	PowerPC e300
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	400MHz
Co-Processors/DSP	Communications; QUICC Engine
RAM Controllers	DDR, DDR2
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (1)
SATA	-
USB	USB 1.x (1)
Voltage - I/O	1.8V, 2.5V, 3.3V
Operating Temperature	-40°C ~ 105°C (TA)
Security Features	-
Package / Case	668-BBGA Exposed Pad
Supplier Device Package	668-PBGA-PGE (29x29)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/kmpc8358cvragdda

- Data bus widths:
  - Single 32-bit data PCI interface that operates at up to 66 MHz
- PCI 3.3-V compatible (not 5-V compatible)
- PCI host bridge capabilities on both interfaces
- PCI agent mode supported on PCI interface
- Support for PCI-to-memory and memory-to-PCI streaming
- Memory prefetching of PCI read accesses and support for delayed read transactions
- Support for posting of processor-to-PCI and PCI-to-memory writes
- On-chip arbitration, supporting five masters on PCI
- Support for accesses to all PCI address spaces
- Parity support
- Selectable hardware-enforced coherency
- Address translation units for address mapping between host and peripheral
- Dual address cycle supported when the device is the target
- Internal configuration registers accessible from PCI

- Local bus controller (LBC)
  - Multiplexed 32-bit address and data operating at up to 133 MHz
  - Eight chip selects support eight external slaves
  - Up to eight-beat burst transfers
  - 32-, 16-, and 8-bit port sizes are controlled by an on-chip memory controller
  - Three protocol engines available on a per chip select basis:
    - General-purpose chip select machine (GPCM)
    - Three user programmable machines (UPMs)
    - Dedicated single data rate SDRAM controller
  - Parity support
  - Default boot ROM chip select with configurable bus width (8-, 16-, or 32-bit)
- Programmable interrupt controller (PIC)
  - Functional and programming compatibility with the MPC8260 interrupt controller
  - Support for 8 external and 35 internal discrete interrupt sources
  - Support for one external (optional) and seven internal machine checkstop interrupt sources
  - Programmable highest priority request
  - Four groups of interrupts with programmable priority
  - External and internal interrupts directed to communication processor
  - Redirects interrupts to external $\overline{\text{INTA}}$ pin when in core disable mode
  - Unique vector number for each interrupt source
- Dual industry-standard I^2C interfaces
  - Two-wire interface

4.3 Gigabit Reference Clock Input Timing

Table 8 provides the Gigabit reference clocks (GTX_CLK125) AC timing specifications.

Table 8. GTX_CLK125 AC Timing Specifications

At recommended operating conditions with LV_{DD} = 2.5 ± 0.125 mV/ 3.3 V ± 165 mV

Parameter/Condition	Symbol	Min	Typical	Max	Unit	Notes
GTX_CLK125 frequency	t_{G125}	—	125	—	MHz	—
GTX_CLK125 cycle time	t_{G125}	—	8	—	ns	—
GTX_CLK rise and fall time LV_{DD} = 2.5 V LV_{DD} = 3.3 V	t_{G125R}/t_{G125F}	—	—	 0.75 1.0	ns	1
GTX_CLK125 duty cycle GMII & TBI 1000Base-T for RGMII & RTBI	t_{G125H}/t_{G125}	 45 47	—	 55 53	%	2
GTX_CLK125 jitter	—	—	—	±150	ps	2

Notes:

1. Rise and fall times for GTX_CLK125 are measured from 0.5 and 2.0 V for LV_{DD} = 2.5 V and from 0.6 and 2.7 V for LV_{DD} = 3.3 V.
2. GTX_CLK125 is used to generate the GTX clock for the UCC Ethernet transmitter with 2% degradation. The GTX_CLK125 duty cycle can be loosened from 47%/53% as long as the PHY device can tolerate the duty cycle generated by GTX_CLK. See Section 8.2.2, “MII AC Timing Specifications,” Section 8.2.3, “RMII AC Timing Specifications,” and Section 8.2.5, “RGMII and RTBI AC Timing Specifications” for the duty cycle for 10Base-T and 100Base-T reference clock.

5 RESET Initialization

This section describes the DC and AC electrical specifications for the reset initialization timing and electrical requirements of the MPC8358E.

5.1 RESET DC Electrical Characteristics

Table 9 provides the DC electrical characteristics for the RESET pins of the device.

Table 9. RESET Pins DC Electrical Characteristics

Characteristic	Symbol	Condition	Min	Max	Unit
Input high voltage	V_{IH}	—	2.0	OV_{DD} + 0.3	V
Input low voltage	V_{IL}	—	–0.3	0.8	V
Input current	I_{IN}	—	—	±10	μA
Output high voltage	V_{OH}	I_{OH} = –8.0 mA	2.4	—	V
Output low voltage	V_{OL}	I_{OL} = 8.0 mA	—	0.5	V

Table 20. DDR and DDR2 SDRAM Output AC Timing Specifications for Source Synchronous Mode (continued)

At recommended operating conditions with GV_{DD} of (1.8 V or 2.5 V) ± 5%.

Parameter[8]	Symbol[1]	Min	Max	Unit	Notes
MDQS epilogue end	t_{DDKHME}	–0.6	0.9	ns	7

Notes:

1. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. Output hold time can be read as DDR timing (DD) from the rising or falling edge of the reference clock (KH or KL) until the output went invalid (AX or DX). For example, t_{DDKHAS} symbolizes DDR timing (DD) for the time t_{MCK} memory clock reference (K) goes from the high (H) state until outputs (A) are setup (S) or output valid time. Also, t_{DDKLDX} symbolizes DDR timing (DD) for the time t_{MCK} memory clock reference (K) goes low (L) until data outputs (D) are invalid (X) or data output hold time.
2. All MCK/$\overline{\text{MCK}}$ referenced measurements are made from the crossing of the two signals ±0.1 V.
3. In the source synchronous mode, MCK/$\overline{\text{MCK}}$ can be shifted in ¼ applied cycle increments through the clock control register. For the skew measurements referenced for t_{AOSKEW} it is assumed that the clock adjustment is set to align the address/command valid with the rising edge of MCK.
4. ADDR/CMD includes all DDR SDRAM output signals except MCK/$\overline{\text{MCK}}$, $\overline{\text{MCS}}$, and MDQ/MECC/MDM/MDQS. For the ADDR/CMD setup and hold specifications, it is assumed that the clock control register is set to adjust the memory clocks by ½ applied cycle.
5. Note that t_{DDKHMH} follows the symbol conventions described in note 1. For example, t_{DDKHMH} describes the DDR timing (DD) from the rising edge of the MCK(n) clock (KH) until the MDQS signal is valid (MH). t_{DDKHMH} can be modified through control of the DQSS override bits in the TIMING_CFG_2 register. In source synchronous mode, this will typically be set to the same delay as the clock adjust in the CLK_CNTL register. The timing parameters listed in the table assume that these two parameters have been set to the same adjustment value. See the *MPC8360E PowerQUICC II Pro Integrated Communications Processor Family Reference Manual* for a description and understanding of the timing modifications enabled by use of these bits.
6. Determined by maximum possible skew between a data strobe (MDQS) and any corresponding bit of data (MDQ), ECC (MECC), or data mask (MDM). The data strobe should be centered inside of the data eye at the pins of the device.
7. All outputs are referenced to the rising edge of MCK(n) at the pins of the device. Note that t_{DDKHMP} follows the symbol conventions described in note 1.
8. AC timing values are based on the DDR data rate, which is twice the DDR memory bus frequency.

Figure 6 shows the DDR SDRAM output timing for address skew with respect to any MCK.

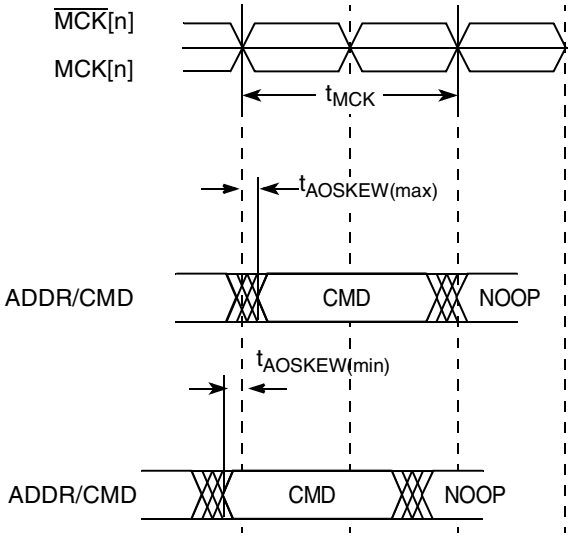

Figure 6. Timing Diagram for t_{AOSKEW} Measurement

Figure 9 shows the GMII transmit AC timing diagram.

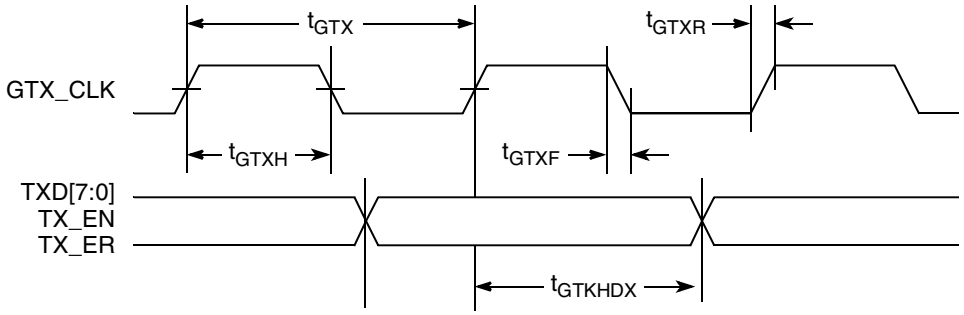

Figure 9. GMII Transmit AC Timing Diagram

8.2.1.2 GMII Receive AC Timing Specifications

Table 27 provides the GMII receive AC timing specifications.

Table 27. GMII Receive AC Timing Specifications

At recommended operating conditions with LV_{DD}/OV_{DD} of 3.3 V ± 10%.

Parameter/Condition	Symbol[1]	Min	Typ	Max	Unit	Notes
RX_CLK clock period	t_{GRX}	—	8.0	—	ns	—
RX_CLK duty cycle	t_{GRXH}/t_{GRX}	40	—	60	%	—
RXD[7:0], RX_DV, RX_ER setup time to RX_CLK	t_{GRDVKH}	2.0	—	—	ns	—
RXD[7:0], RX_DV, RX_ER hold time to RX_CLK	t_{GRDXKH}	0.3	—	—	ns	—
RX_CLK clock rise time, (20% to 80%)	t_{GRXR}	—	—	1.0	ns	—
RX_CLK clock fall time, (80% to 20%)	t_{GRXF}	—	—	1.0	ns	—

Notes:

1. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{GRDVKH} symbolizes GMII receive timing (GR) with respect to the time data input signals (D) reaching the valid state (V) relative to the t_{RX} clock reference (K) going to the high state (H) or setup time. Also, t_{GRDXKL} symbolizes GMII receive timing (GR) with respect to the time data input signals (D) went invalid (X) relative to the t_{GRX} clock reference (K) going to the low (L) state or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{GRX} represents the GMII (G) receive (RX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).

Figure 10 shows the GMII receive AC timing diagram.

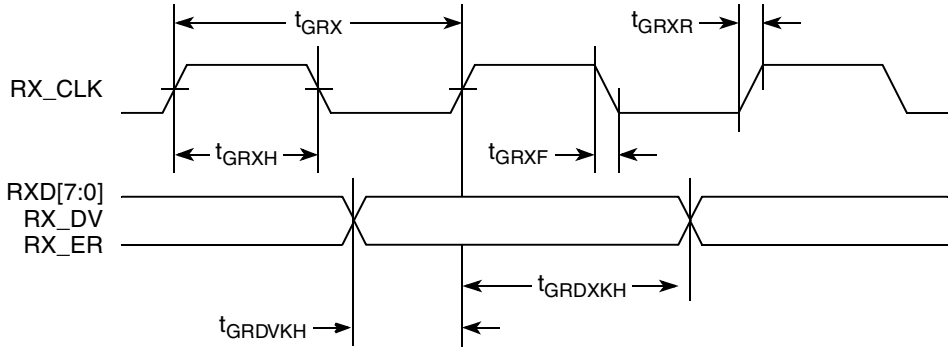

Figure 10. GMII Receive AC Timing Diagram

8.2.2 MII AC Timing Specifications

This section describes the MII transmit and receive AC timing specifications.

8.2.2.1 MII Transmit AC Timing Specifications

Table 28 provides the MII transmit AC timing specifications.

Table 28. MII Transmit AC Timing Specifications

At recommended operating conditions with LV_{DD}/OV_{DD} of 3.3 V ± 10%.

Parameter/Condition	Symbol[1]	Min	Typ	Max	Unit
TX_CLK clock period 10 Mbps	t_{MTX}	—	400	—	ns
TX_CLK clock period 100 Mbps	t_{MTX}	—	40	—	ns
TX_CLK duty cycle	t_{MTXH}/t_{MTX}	35	—	65	%
TX_CLK to MII data TXD[3:0], TX_ER, TX_EN delay	t_{MTKHDX} t_{MTKHDV}	1 —	5	— 15	ns
TX_CLK data clock rise time, (20% to 80%)	t_{MTXR}	1.0	—	4.0	ns
TX_CLK data clock fall time, (80% to 20%)	t_{MTXF}	1.0	—	4.0	ns

Note:

1. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{MTKHDX} symbolizes MII transmit timing (MT) for the time t_{MTX} clock reference (K) going high (H) until data outputs (D) are invalid (X). Note that, in general, the clock reference symbol representation is based on two to three letters representing the clock of a particular functional. For example, the subscript of t_{MTX} represents the MII(M) transmit (TX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).

Figure 17 shows the TBI transmit AC timing diagram.

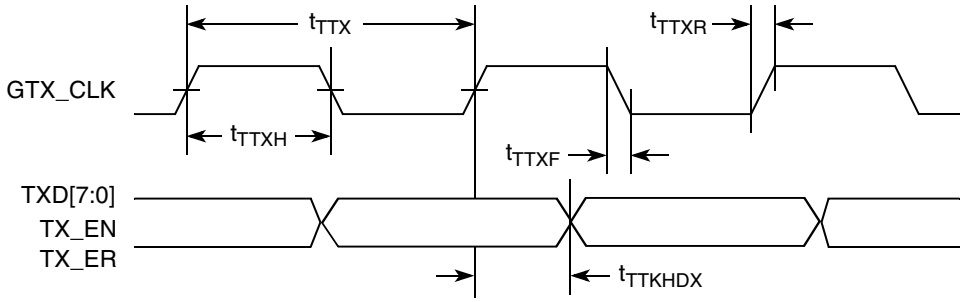

Figure 17. TBI Transmit AC Timing Diagram

8.2.4.2 TBI Receive AC Timing Specifications

Table 33 provides the TBI receive AC timing specifications.

Table 33. TBI Receive AC Timing Specifications

At recommended operating conditions with LV_{DD}/OV_{DD} of 3.3 V ± 10%.

Parameter/Condition	Symbol[1]	Min	Typ	Max	Unit	Notes
PMA_RX_CLK clock period	t_{TRX}	—	16.0	—	ns	—
PMA_RX_CLK skew	t_{SKTRX}	7.5	—	8.5	ns	—
RX_CLK duty cycle	t_{TRXH}/t_{TRX}	40	—	60	%	—
RCG[9:0] setup time to rising PMA_RX_CLK	t_{TRDVKH}	2.5	—	—	ns	2
RCG[9:0] hold time to rising PMA_RX_CLK	t_{TRDXKH}	1.0	—	—	ns	2
RX_CLK clock rise time, V_{IL}(min) to V_{IH}(max)	t_{TRXR}	0.7	—	2.4	ns	—
RX_CLK clock fall time, V_{IH}(max) to V_{IL}(min)	t_{TRXF}	0.7	—	2.4	ns	—

Notes:

1. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{TRDVKH} symbolizes TBI receive timing (TR) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{TRX} clock reference (K) going to the high (H) state or setup time. Also, t_{TRDXKH} symbolizes TBI receive timing (TR) with respect to the time data input signals (D) went invalid (X) relative to the t_{TRX} clock reference (K) going to the high (H) state. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{TRX} represents the TBI (T) receive (RX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall). For symbols representing skews, the subscript is skew (SK) followed by the clock that is being skewed (TRX).
2. Setup and hold time of even numbered RCG are measured from riding edge of PMA_RX_CLK1. Setup and hold time of odd numbered RCG are measured from riding edge of PMA_RX_CLK0.

Table 34. RGMII and RTBI AC Timing Specifications (continued)

At recommended operating conditions with LV_{DD} of 2.5 V ± 5%.

Parameter/Condition	Symbol[1]	Min	Typ	Max	Unit	Notes
GTX_CLK125 reference clock duty cycle	t_{G125H}/t_{G125}	47	—	53	%	—

Notes:

1. Note that, in general, the clock reference symbol representation for this section is based on the symbols RGT to represent RGMII and RTBI timing. For example, the subscript of t_{RGT} represents the TBI (T) receive (Rx) clock. Note also that the notation for rise (R) and fall (F) times follows the clock symbol that is being represented. For symbols representing skews, the subscript is skew (SK) followed by the clock that is being skewed (RGT).
2. This implies that PC board design will require clocks to be routed such that an additional trace delay of greater than 1.5 ns will be added to the associated clock signal.
3. For 10 and 100 Mbps, t_{RGT} scales to 400 ns ± 40 ns and 40 ns ± 4 ns, respectively.
4. Duty cycle may be stretched/shrunk during speed changes or while transitioning to a received packet's clock domains as long as the minimum duty cycle is not violated and stretching occurs for no more than three t_{RGT} of the lowest speed transitioned between.
5. Duty cycle reference is $LV_{DD}/2$.
6. This symbol is used to represent the external GTX_CLK125 and does not follow the original symbol naming convention.
7. In rev. 2.1 silicon, due to errata, $t_{SKRGTKHDX}$ minimum is –0.65 ns for UCC2 option 1 and –0.9 for UCC2 option 2, and $t_{SKRGTKHDV}$ maximum is 0.75 ns for UCC1 and UCC2 option 1 and 0.85 for UCC2 option 2. UCC1 does meet $t_{SKRGTKHDX}$ minimum for rev. 2.1 silicon.

Figure 19 shows the RGMII and RTBI AC timing and multiplexing diagrams.

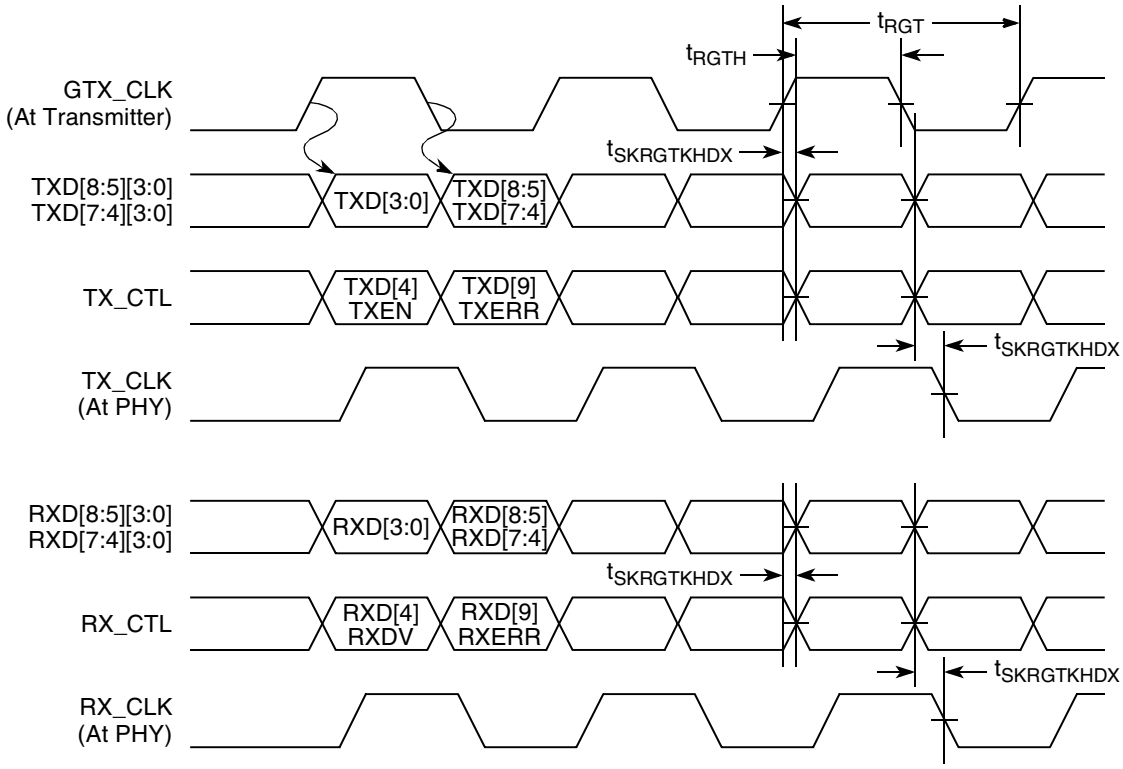

Figure 19. RGMII and RTBI AC Timing and Multiplexing Diagrams

Table 36. MII Management AC Timing Specifications (continued)

At recommended operating conditions with LV_{DD} is 3.3 V ± 10%.

Parameter/Condition	Symbol[1]	Min	Typ	Max	Unit	Notes
MDC fall time	t_{MDHF}	—	—	10	ns	—

Notes:

1. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{MDKHDX} symbolizes management data timing (MD) for the time t_{MDC} from clock reference (K) high (H) until data outputs (D) are invalid (X) or data hold time. Also, $t_{MDRDVKH}$ symbolizes management data timing (MD) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{MDC} clock reference (K) going to the high (H) state or setup time. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
2. This parameter is dependent on the csb_clk speed (that is, for a csb_clk of 267 MHz, the maximum frequency is 8.3 MHz and the minimum frequency is 1.2 MHz; for a csb_clk of 375 MHz, the maximum frequency is 11.7 MHz and the minimum frequency is 1.7 MHz).
3. This parameter is dependent on the ce_clk speed (that is, for a ce_clk of 200 MHz, the delay is 90 ns and for a ce_clk of 300 MHz, the delay is 63 ns).

Figure 20 shows the MII management AC timing diagram.

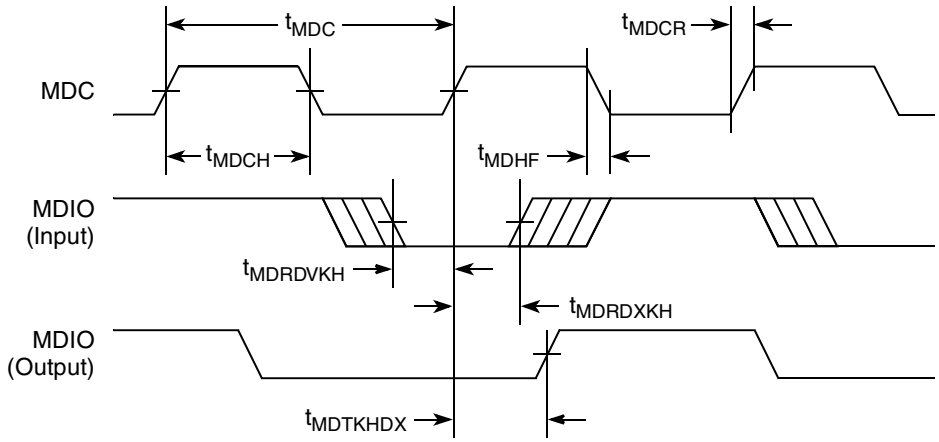

Figure 20. MII Management Interface Timing Diagram

8.3.3 IEEE 1588 Timer AC Specifications

Table 37 provides the IEEE 1588 timer AC specifications.

Table 37. IEEE 1588 Timer AC Specifications

Parameter	Symbol	Min	Max	Unit	Notes
Timer clock frequency	t_{TMRCK}	0	70	MHz	1
Input setup to timer clock	t_{TMRCKS}	—	—	—	2, 3
Input hold from timer clock	t_{TMRCKH}	—	—	—	2, 3
Output clock to output valid	t_{GCLKNV}	0	6	ns	—

Table 47. PCI AC Timing Specifications at 33 MHz

Parameter	Symbol[1]	Min	Max	Unit	Notes
Clock to output valid	t_{PCKHOV}	—	11	ns	2
Output hold from clock	t_{PCKHOX}	2	—	ns	2
Clock to output high impedance	t_{PCKHOZ}	—	14	ns	2, 3
Input setup to clock	t_{PCIVKH}	7.0	—	ns	2, 4
Input hold from clock	t_{PCIXKH}	0.3	—	ns	2, 4

Notes:

1. The symbols used for timing specifications herein follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{PCIVKH} symbolizes PCI timing (PC) with respect to the time the input signals (I) reach the valid state (V) relative to the PCI_SYNC_IN clock, t_{SYS}, reference (K) going to the high (H) state or setup time. Also, t_{PCRHFV} symbolizes PCI timing (PC) with respect to the time hard reset (R) went high (H) relative to the frame signal (F) going to the valid (V) state.
2. See the timing measurement conditions in the *PCI 2.2 Local Bus Specifications*.
3. For purposes of active/float timing measurements, the Hi-Z or off-state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.
4. Input timings are measured at the pin.

Figure 35 provides the AC test load for PCI.

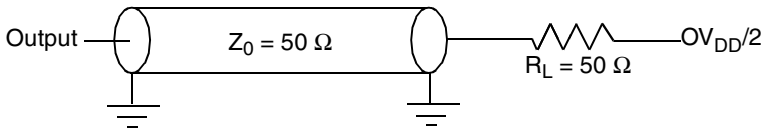

Figure 35. PCI AC Test Load

Figure 36 shows the PCI input AC timing conditions.

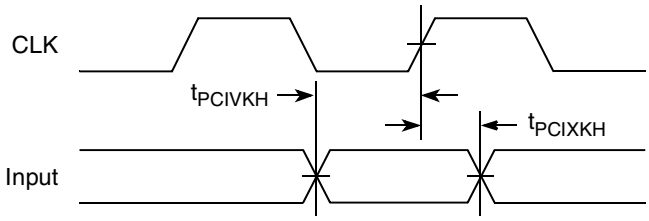

Figure 36. PCI Input AC Timing Measurement Conditions

16.1 SPI DC Electrical Characteristics

Table 54 provides the DC electrical characteristics for the device SPI.

Table 54. SPI DC Electrical Characteristics

Characteristic	Symbol	Condition	Min	Max	Unit
Output high voltage	V_{OH}	I_{OH} = –6.0 mA	2.4	—	V
Output low voltage	V_{OL}	I_{OL} = 6.0 mA	—	0.5	V
Output low voltage	V_{OL}	I_{OL} = 3.2 mA	—	0.4	V
Input high voltage	V_{IH}	—	2.0	OV_{DD} + 0.3	V
Input low voltage	V_{IL}	—	–0.3	0.8	V
Input current	I_{IN}	0 V ≤ V_{IN} ≤ OV_{DD}	—	±10	μA

16.2 SPI AC Timing Specifications

Table 55 and provide the SPI input and output AC timing specifications.

Table 55. SPI AC Timing Specifications[1]

Characteristic	Symbol[2]	Min	Max	Unit
SPI outputs—Master mode (internal clock) delay	t_{NIKHOX} t_{NIKHOV}	0.4 —	— 8	ns
SPI outputs—Slave mode (external clock) delay	t_{NEKHOX} t_{NEKHOV}	2 —	— 8	ns
SPI inputs—Master mode (internal clock) input setup time	t_{NIIVKH}	8	—	ns
SPI inputs—Master mode (internal clock) input hold time	t_{NIIXKH}	0	—	ns
SPI inputs—Slave mode (external clock) input setup time	t_{NEIVKH}	4	—	ns
SPI inputs—Slave mode (external clock) input hold time	t_{NEIXKH}	2	—	ns

Notes:
1. Output specifications are measured from the 50% level of the rising edge of CLKIN to the 50% level of the signal. Timings are measured at the pin.
2. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{NIKHOV} symbolizes the NMSI outputs internal timing (NI) for the time t_{SPI} memory clock reference (K) goes from the high state (H) until outputs (O) are valid (V).

Figure 40 provides the AC test load for the SPI.

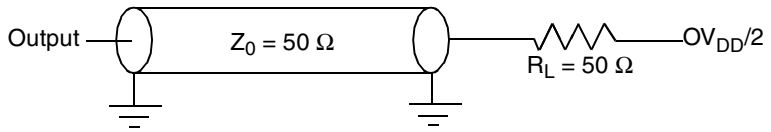

Figure 40. SPI AC Test Load

4. Datum A, the seating plane, is determined by the spherical crowns of the solder balls.
5. Parallelism measurement must exclude any effect of mark on top surface of package.
6. Distance from the seating plane to the encapsulant material.

21.3 Pinout Listings

Refer to AN3097, “MPC8360/MPC8358E PowerQUICC Design Checklist,” for proper pin termination and usage.

Table 65 shows the pin list of the MPC8358E PBGA package.

Table 65. MPC8358E PBGA Pinout Listing

Signal	Package Pin Number	Pin Type	Power Supply	Notes
DDR SDRAM Memory Controller Interface				
MEMC_MDQ[0:63]	AD20, AG24, AF24, AH24, AF23, AE22, AH26, AD21, AH25, AD22, AF27, AB24, AG25, AC22, AE25, AC24, AD25, AB25, AC25, AG28, AD26, AE23, AG26, AC26, AD27, V25, AA28, AA25, Y26, W27, U24, W24, E28, H24, E26, D25, G27, H25, G26, F26, F27, F25, D26, F24, G25, E27, D27, C28, C27, F22, B26, F21, B28, E22, D24, C24, A25, E20, F20, D20, A23, C21, C23, E19	I/O	GV_{DD}	—
MEMC_MECC[0:7]	N26, N24, J26, H28, N28, P24, L26, K24	I/O	GV_{DD}	—
MEMC_MDM[0:8]	AG23, AD23, AE26, V28, G28, D28, D23, B24, U27	O	GV_{DD}	—
MEMC_MDQS[0:8]	AH23, AH27, AF28, T28, H26, E25, B25, A24, R28	I/O	GV_{DD}	—
MEMC_MBA[0:2]	V26, W28, Y28	O	GV_{DD}	—
MEMC_MA[0:14]	L25, M25, M24, K28, P28, T24, M27, R25, P25, L28, U26, M28, L27, K27, H27	O	GV_{DD}	—
MEMC_MODT[0:3]	AE21, AC19, E23, B23	—	GV_{DD}	6
$\overline{\text{MEMC\_MWE}}$	R27	O	GV_{DD}	—
$\overline{\text{MEMC\_MRAS}}$	W25	O	GV_{DD}	—
$\overline{\text{MEMC\_MCAS}}$	R24	O	GV_{DD}	—
$\overline{\text{MEMC\_MCS}}$[0:3]	T26, U28, J25, F28	O	GV_{DD}	—
MEMC_MCKE[0:1]	AD24, AE28	O	GV_{DD}	—
MEMC_MCK[0:5]	AG22, AG27, A26, C26, P26, E21	O	GV_{DD}	—
$\overline{\text{MEMC\_MCK}}$[0:5]	AF22, AF26, A27, B27, N27, D22	O	GV_{DD}	—
MDIC[0:1]	F19, AA27	I/O	GV_{DD}	11
PCI				
$\overline{\text{PCI\_INTA}}$/ PF[5]	R3	I/O	$LV_{DD}2$	2
$\overline{\text{PCI\_RESET\_OUT}}$/ PF[6]	P6	I/O	$LV_{DD}2$	—
PCI_AD[0:31]/ PG[0:31]	AB5, AC5, AG1, AA5, AF2, AD4, Y6, AF1, AE2, AC4, AD3, AE1, Y4, AC3, AD2, AD1, AB2, Y3, AA1, Y1, W1, V6, W3, V4, T5, W2, V5, V1, U4, V2, U2, T2	I/O	$LV_{DD}2$	—
$\overline{\text{PCI\_C\_BE}}$[0:3]/ PF[7:10]	Y5, AC2, Y2, U5	I/O	OV_{DD}	—

Table 65. MPC8358E PBGA Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
LGPL2/ LSDRAS/ LOE	AH19	O	OV_{DD}	—
LGPL3/ LSDCAS/ cfg_reset_source2	AE18	I/O	OV_{DD}	—
LGPL4/ LGTA/ LUPWAIT/ LPBSE	AG19	I/O	OV_{DD}	—
LGPL5/ cfg_clkin_div	AF19	I/O	OV_{DD}	—
LCKE	AD8	O	OV_{DD}	—
LCLK[0]	AC9	O	OV_{DD}	—
LCLK[1]/ LCS[6]	AG6	O	OV_{DD}	—
LCLK[2]/ LCS[7]	AE7	O	OV_{DD}	—
LSYNC_OUT	AG4	O	OV_{DD}	—
LSYNC_IN	AC8	I	OV_{DD}	—
Programmable Interrupt Controller				
MCP_OUT	AG3	O	OV_{DD}	2
IRQ0/ MCP_IN	AH4	I	OV_{DD}	—
IRQ[1:2]	AG5, AH5	I/O	OV_{DD}	—
IRQ[3]/ CORE_SRESET	AD7	I/O	OV_{DD}	—
IRQ[4:5]	AC7, AD6	I/O	OV_{DD}	—
IRQ[6:7]	AC6, AC10	I/O	OV_{DD}	—
DUART				
UART1_SOUT	AE3	O	OV_{DD}	—
UART1_SIN	AE4	I/O	OV_{DD}	—
UART1_CTS	AG2	I/O	OV_{DD}	—
UART1_RTS	AA6	O	OV_{DD}	—
I^2C Interface				
IIC1_SDA	AB6	I/O	OV_{DD}	2
IIC1_SCL	AD5	I/O	OV_{DD}	2
IIC2_SDA	AF3	I/O	OV_{DD}	2
IIC2_SCL	AH2	I/O	OV_{DD}	2
QUICC Engine				
CE_PA[0]	F6	I/O	$LV_{DD}0$	—

Table 65. MPC8358E PBGA Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
TDI	AE8	I	OV_{DD}	4
TDO	AG7	O	OV_{DD}	3
TMS	AH7	I	OV_{DD}	4
$\overline{\text{TRST}}$	AG8	I	OV_{DD}	4
Test				
TEST	AF9	I	OV_{DD}	7
$\overline{\text{TEST\_SEL}}$	AE27	I	GV_{DD}	9
PMC				
$\overline{\text{QUIESCE}}$	AF4	O	OV_{DD}	—
System Control				
$\overline{\text{PORESET}}$	AE9	I	OV_{DD}	—
$\overline{\text{HRESET}}$	AG9	I/O	OV_{DD}	1
$\overline{\text{SRESET}}$	AH10	I/O	OV_{DD}	2
Thermal Management				
THERM0	K25	I	GV_{DD}	—
THERM1	AA26	I	GV_{DD}	—
Power and Ground Signals				
$AV_{DD}1$	AF8	Power for LBIU DLL (1.2 V)	$AV_{DD}1$	—
$AV_{DD}2$	AH8	Power for CE PLL (1.2 V)	$AV_{DD}2$	—
$AV_{DD}5$	AB26	Power for e300 PLL (1.2 V)	$AV_{DD}5$	—
$AV_{DD}6$	AH9	Power for system PLL (1.2 V)	$AV_{DD}6$	—
GND	C16, D11, D21, E24, F7, J10, J12, J15, J16, J17, J28, K11, K13, K14, K17, K18, L4, L9, L11, L12, L13, L14, L15, L16, L17, L18, L19, L24, M10, M11, M14, M15, M18, M19, N11, N18, N25, P9, P11, P18, P19, R9, R11, R14, R15, R18, R19, R26, T10, T11, T14, T15, T18, T25, U10, U11, U18, V9, V11, V14, V15, V18, V24, V27, W18, W19, Y11, Y14, Y18, Y19, Y25, Y27, AB4, AB27, AC27, AE20, AE24, AF5, AF15, AG10	—	—	—

Note that *lb_clk* is not the external local bus or DDRC2 frequency; *lb_clk* passes through the a LB clock divider to create the external local bus clock outputs (LSYNC_OUT and LCLK[0:2]). The LB clock divider ratio is controlled by LCRR[CLKDIV].

In addition, some of the internal units may be required to be shut off or operate at lower frequency than the *csb_clk* frequency. Those units have a default clock ratio that can be configured by a memory mapped register after the device comes out of reset. Table 66 specifies which units have a configurable clock frequency.

Table 66. Configurable Clock Units

Unit	Default Frequency	Options
Security core	*csb_clk*/3	Off, *csb_clk*[1], *csb_clk*/2, *csb_clk*/3
PCI and DMA complex	csb_clk	Off, *csb_clk*

1 With limitation, only for slow csb_clk rates, up to 166 MHz.

Table 67 provides the operating frequencies for the PBGA package under recommended operating conditions (see Table 2). All frequency combinations shown in the table below may not be available. Maximum operating frequencies depend on the part ordered, see Section 25.1, "Part Numbers Fully Addressed by this Document," for part ordering details and contact your Freescale sales representative or authorized distributor for more information.

Table 67. Operating Frequencies for the PBGA Package

Characteristic[1]	400 MHz	Unit
e300 core frequency (*core_clk*)	266–400	MHz
Coherent system bus frequency (*csb_clk*)	133–266	MHz
QUICC Engine frequency (*ce_clk*)	266–400	MHz
DDR and DDR2 memory bus frequency (MCLK)[2]	100–133	MHz
Local bus frequency (LCLK*n*)[3]	16.67–133	MHz
PCI input frequency (CLKIN or PCI_CLK)	25–66.67	MHz
Security core maximum internal operating frequency	133	MHz

1 The CLKIN frequency, RCWL[SPMF], and RCWL[COREPLL] settings must be chosen such that the resulting *csb_clk*, MCLK, LCLK[0:2], and *core_clk* frequencies do not exceed their respective maximum or minimum operating frequencies.

2 The DDR data rate is 2x the DDR memory bus frequency.

3 The local bus frequency is 1/2, 1/4, or 1/8 of the *lb_clk* frequency (depending on LCRR[CLKDIV]) which is in turn 1x or 2x the *csb_clk* frequency (depending on RCWL[LBCM]).

22.1 System PLL Configuration

The system PLL is controlled by the RCWL[SPMF] and RCWL[SVCOD] parameters. Table 68 shows the multiplication factor encodings for the system PLL.

Table 68. System PLL Multiplication Factors

RCWL[SPMF]	System PLL Multiplication Factor
0000	× 16
0001	Reserved
0010	× 2
0011	× 3
0100	× 4
0101	× 5
0110	× 6
0111	× 7
1000	× 8
1001	× 9
1010	× 10
1011	× 11
1100	× 12
1101	× 13
1110	× 14
1111	× 15

The RCWL[SVCOD] denotes the system PLL VCO internal frequency as shown in Table 69.

Table 69. System PLL VCO Divider

RCWL[SVCOD]	VCO Divider
00	4
01	8
10	2
11	Reserved

NOTE

The VCO divider must be set properly so that the system VCO frequency is in the range of 600–1400 MHz.

Table 72. QUICC Engine Block PLL Multiplication Factors (continued)

RCWL[CEPMF]	RCWL[CEPDF]	QUICC Engine PLL Multiplication Factor = RCWL[CEPMF]/ (1 + RCWL[CEPDF])
01011	1	× 5.5
01101	1	× 6.5
01111	1	× 7.5
10001	1	× 8.5
10011	1	× 9.5
10101	1	× 10.5
10111	1	× 11.5
11001	1	× 12.5
11011	1	× 13.5
11101	1	× 14.5

Note:
1. Reserved modes are not listed.

The RCWL[CEVCOD] denotes the QUICC Engine Block PLL VCO internal frequency as shown in Table 73.

Table 73. QUICC Engine Block PLL VCO Divider

RCWL[CEVCOD]	VCO Divider
00	4
01	8
10	2
11	Reserved

NOTE

The VCO divider (RCWL[CEVCOD]) must be set properly so that the QUICC Engine block VCO frequency is in the range of 600–1400 MHz. The QUICC Engine block frequency is not restricted by the CSB and core frequencies. The CSB, core, and QUICC Engine block frequencies should be selected according to the performance requirements.

The QUICC Engine block VCO frequency is derived from the following equations:

ce_clk = (primary clock input × CEPMF) ÷ (1 + CEPDF)

QE VCO Frequency = *ce_clk* × VCO divider × (1 + CEPDF)

22.4 Suggested PLL Configurations

To simplify the PLL configurations, the device might be separated into two clock domains. The first domain contains the CSB PLL and the core PLL. The core PLL is connected serially to the CSB PLL, and has the csb_clk as its input clock. The second clock domain has the QUICC Engine block PLL. The clock domains are independent, and each of their PLLs are configured separately. Both of the domains has one common input clock. Table 74 shows suggested PLL configurations for 33 and 66 MHz input clocks and illustrates each of the clock domains separately. Any combination of clock domains setting with same input clock are valid. Refer to Section 22, "Clocking," for the appropriate operating frequencies for your device.

Table 74. Suggested PLL Configurations

Conf No.[1]	SPMF	CORE PLL	CEPMF	CEPDF	Input Clock Freq (MHz)	CSB Freq (MHz)	Core Freq (MHz)	QUICC Engine Freq (MHz)	400 (MHz)	533 (MHz)	667 (MHz)
33 MHz CLKIN/PCI_SYNC_IN Options											
s1	**0100**	**0000100**	æ	æ	33	133	266	—	∞	∞	∞
s2	**0100**	**0000101**	æ	æ	33	133	333	—	∞	∞	∞
s3	**0101**	**0000100**	æ	æ	33	166	333	—	∞	∞	∞
s4	**0101**	**0000101**	æ	æ	33	166	416	—	—	∞	∞
s5	**0110**	**0000100**	æ	æ	33	200	400	—	∞	∞	∞
s6	**0110**	**0000110**	æ	æ	33	200	600	—	—	—	∞
s7	**0111**	**0000011**	æ	æ	33	233	350	—	∞	∞	∞
s8	**0111**	**0000100**	æ	æ	33	233	466	—	—	∞	∞
s9	**0111**	**0000101**	æ	æ	33	233	583	—	—	—	∞
s10	**1000**	**0000011**	æ	æ	33	266	400	—	∞	∞	∞
s11	**1000**	**0000100**	æ	æ	33	266	533	—	—	∞	∞
s12	**1000**	**0000101**	æ	æ	33	266	667	—	—	—	∞
s13	**1001**	**0000010**	æ	æ	33	300	300	—	∞	∞	∞
s14	**1001**	**0000011**	æ	æ	33	300	450	—	—	∞	∞
s15	**1001**	**0000100**	æ	æ	33	300	600	—	—	—	∞
s16	**1010**	**0000010**	æ	æ	33	333	333	—	∞	∞	∞
s17	**1010**	**0000011**	æ	æ	33	333	500	—	—	∞	∞
s18	**1010**	**0000100**	æ	æ	33	333	667	—	—	—	∞
c1	æ	æ	**01001**	**0**	33	—	—	300	∞	∞	∞
c2	æ	æ	**01100**	**0**	33	—	—	400	∞	∞	∞
c3	æ	æ	**01110**	**0**	33	—	—	466	—	∞	∞
c4	æ	æ	**01111**	**0**	33	—	—	500	—	∞	∞

23.2.3 Experimental Determination of Junction Temperature

To determine the junction temperature of the device in the application after prototypes are available, the Thermal Characterization Parameter (Ψ_{JT}) can be used to determine the junction temperature with a measurement of the temperature at the top center of the package case using the following equation:

$$T_J = T_T + (\Psi_{JT} \times P_D)$$

where:

T_J = junction temperature (°C)
T_T = thermocouple temperature on top of package (°C)
Ψ_{JT} = junction-to-ambient thermal resistance (°C/W)
P_D = power dissipation in the package (W)

The thermal characterization parameter is measured per JESD51-2 specification using a 40 gauge type T thermocouple epoxied to the top center of the package case. The thermocouple should be positioned so that the thermocouple junction rests on the package. A small amount of epoxy is placed over the thermocouple junction and over about 1 mm of wire extending from the junction. The thermocouple wire is placed flat against the package case to avoid measurement errors caused by cooling effects of the thermocouple wire.

23.2.4 Heat Sinks and Junction-to-Ambient Thermal Resistance

In some application environments, a heat sink will be required to provide the necessary thermal management of the device. When a heat sink is used, the thermal resistance is expressed as the sum of a junction to case thermal resistance and a case to ambient thermal resistance:

$$R_{\theta JA} = R_{\theta JC} + R_{\theta CA}$$

where:

$R_{\theta JA}$ = junction-to-ambient thermal resistance (°C/W)
$R_{\theta JC}$ = junction-to-case thermal resistance (°C/W)
$R_{\theta CA}$ = case-to-ambient thermal resistance (°C/W)

$R_{\theta JC}$ is device related and cannot be influenced by the user. The user controls the thermal environment to change the case-to-ambient thermal resistance, $R_{\theta CA}$. For instance, the user can change the size of the heat sink, the airflow around the device, the interface material, the mounting arrangement on printed-circuit board, or change the thermal dissipation on the printed-circuit board surrounding the device.

To illustrate the thermal performance of the devices with heat sinks, the thermal performance has been simulated with a few commercially available heat sinks. The heat sink choice is determined by the application environment (temperature, airflow, adjacent component power dissipation) and the physical space available. Because there is not a standard application environment, a standard heat sink is not required.

23.3.1 Experimental Determination of the Junction Temperature with a Heat Sink

When heat sink is used, the junction temperature is determined from a thermocouple inserted at the interface between the case of the package and the interface material. A clearance slot or hole is normally required in the heat sink. Minimizing the size of the clearance is important to minimize the change in thermal performance caused by removing part of the thermal interface to the heat sink. Because of the experimental difficulties with this technique, many engineers measure the heat sink temperature and then back calculate the case temperature using a separate measurement of the thermal resistance of the interface. From this case temperature, the junction temperature is determined from the junction-to-case thermal resistance.

$$T_J = T_C + (R_{\theta JC} \times P_D)$$

where:

T_J = junction temperature (°C)

T_C = case temperature of the package (°C)

$R_{\theta JC}$ = junction to case thermal resistance (°C/W)

P_D = power dissipation (W)

24 System Design Information

This section provides electrical and thermal design recommendations for successful application of the MPC8358E. Additional information can be found in *MPC8360E/MPC8358E PowerQUICC Design Checklist* (AN3097).

24.1 System Clocking

The device includes two PLLs, as follows.

- The platform PLL ($AV_{DD}1$) generates the platform clock from the externally supplied CLKIN input. The frequency ratio between the platform and CLKIN is selected using the platform PLL ratio configuration bits as described in Section 22.1, “System PLL Configuration.”
- The e300 core PLL ($AV_{DD}2$) generates the core clock as a slave to the platform clock. The frequency ratio between the e300 core clock and the platform clock is selected using the e300 PLL ratio configuration bits as described in Section 22.2, “Core PLL Configuration.”

24.2 PLL Power Supply Filtering

Each of the PLLs listed above is provided with power through independent power supply pins ($AV_{DD}1$, $AV_{DD}2$, respectively). The AV_{DD} level should always be equivalent to V_{DD}, and preferably these voltages will be derived directly from V_{DD} through a low frequency filter scheme such as the following.

There are a number of ways to reliably provide power to the PLLs, but the recommended solution is to provide five independent filter circuits as illustrated in Figure 54, one to each of the five AV_{DD} pins. By providing independent filters to each PLL, the opportunity to cause noise injection from one PLL to the other is reduced.

26 Document Revision History

Table 80 provides a revision history for this hardware specification.

Table 80. Revision History

Rev. Number	Date	Substantive Change(s)
3	01/2011	• Updated references to the LCRR register throughout • Removed references to DDR DLL mode in Section 6.2.2, “DDR and DDR2 SDRAM Output AC Timing Specifications.” • Changed “Junction-to-Case” to “Junction-to-Ambient” in Section 23.2.4, “Heat Sinks and Junction-to-Ambient Thermal Resistance,” and Table 76, “Heat Sinks and Junction-to-Ambient Thermal Resistance of PBGA Package,” titles.
2	03/2010	• Changed references to RCWH[PCICKEN] to RCWH[PCICKDRV]. • In Table 2, added extended temperature characteristics. • Added Figure 5, “DDR Input Timing Diagram.” • In Figure 52, “Mechanical Dimensions and Bottom Surface Nomenclature of the PBGA Package,” removed watermark. • In Table 4, “MPC8358E PBGA Core Power Dissipation[1],” added row for 400/266/400 part offering. • Updated the title of Table 18,”DDR SDRAM Input AC Timing Specifications.” • In Table 19, “DDR and DDR2 SDRAM Input AC Timing Specifications Mode,” changed table subtitle. • In Table 26–Table 29, and Table 32—Table 33, changed the rise and fall time specifications to reference 20–80% and 80–20% of the voltage supply, respectively. • In Table 37, “IEEE 1588 Timer AC Specifications,” changed first parameter to “Timer clock frequency.” • In Table 44, “I2C AC Electrical Specifications,” changed units to “ns” for t_{I2DVKH}. • In Table 65 “MPC8358E PBGA Pinout Listing, added note 7: “This pin must always be tied to GND” to the TEST pin. • In Table 67, “Operating Frequencies for the PBGA Package,” and Table 78, “Part Numbering Nomenclature,” updated for 400 MHz QE part offering • In Section 4, “Clock Input Timing,” added note regarding rise/fall time on QUICC Engine block input pins. • Added Section 4.3, “Gigabit Reference Clock Input Timing.” • Updated Section 8.1.1, “10/100/1000 Ethernet DC Electrical Characteristics.” • In Section 21.3, “Pinout Listings,” added sentence stating “Refer to AN3097, ‘MPC8360/MPC8358E PowerQUICC Design Checklist,’ for proper pin termination and usage.” • In Section 22, “Clocking,” removed statement: “The OCCR[PCICDn] parameters select whether CLKIN or CLKIN/2 is driven out on the PCI_CLK_OUTn signals.” • In Section 22.1, “System PLL Configuration,” updated the system VCO frequency conditions. • In Table 78, added extended temperature characteristics.
1	12/2007	Initial release.